

## features

- **Fast Throughput Rate:** 1.25 MSPS at 5 V,  
625 KSPS at 3 V
- **Wide Analog Input:** 0 V to AV<sub>DD</sub>
- **Differential Nonlinearity Error:** < ± 0.5 LSB
- **Integral Nonlinearity Error:** < ± 0.5 LSB
- **Single 2.7-V to 5.5-V Supply Operation**
- **Low Power:** 12 mW at 3 V and 35 mW at 5 V
- **Auto Power Down of 1 mA Max**
- **Software Power Down:** 10 µA Max
- **Internal OSC**
- **Hardware Configurable**
- **DSP and Microcontroller Compatible Parallel Interface**
- **Binary/Twos Complement Output**
- **Hardware Controlled Extended Sampling**
- **Hardware or Software Start of Conversion**

## description

The TLV571 is an 8-bit data acquisition system that combines a high-speed 8-bit ADC and a parallel interface. The device contains two on-chip control registers allowing control of software conversion start and power down via the bidirectional parallel port. The control registers can be set to a default mode using a dummy RD while WR is tied low allowing the registers to be hardware configurable.

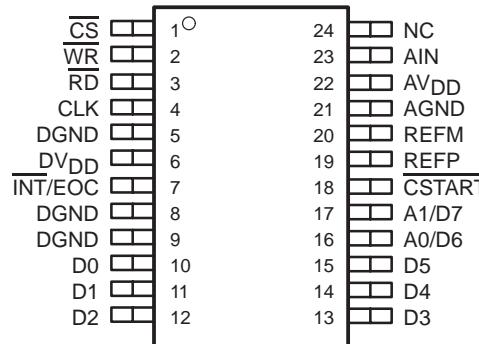
The TLV571 operates from a single 2.7-V to 5.5-V power supply. It accepts an analog input range from 0 V to AV<sub>DD</sub> and digitizes the input at a maximum 1.25 MSPS throughput rate at 5 V. The power dissipations are only 12 mW with a 3-V supply or 35 mW with a 5-V supply. The device features an auto power-down mode that automatically powers down to 1 mA 50 ns after conversion is performed. In software power-down mode, the ADC is further powered down to only 10 µA.

Very high throughput rate, simple parallel interface, and low power consumption make the TLV571 an ideal choice for high-speed digital signal processing.

## applications

- **Mass Storage and HDD**
- **Automotive**
- **Digital Servos**
- **Process Control**
- **General-Purpose DSP**
- **Image Sensor Processing**

DW OR PW PACKAGE  
(TOP VIEW)



NC – No internal connection

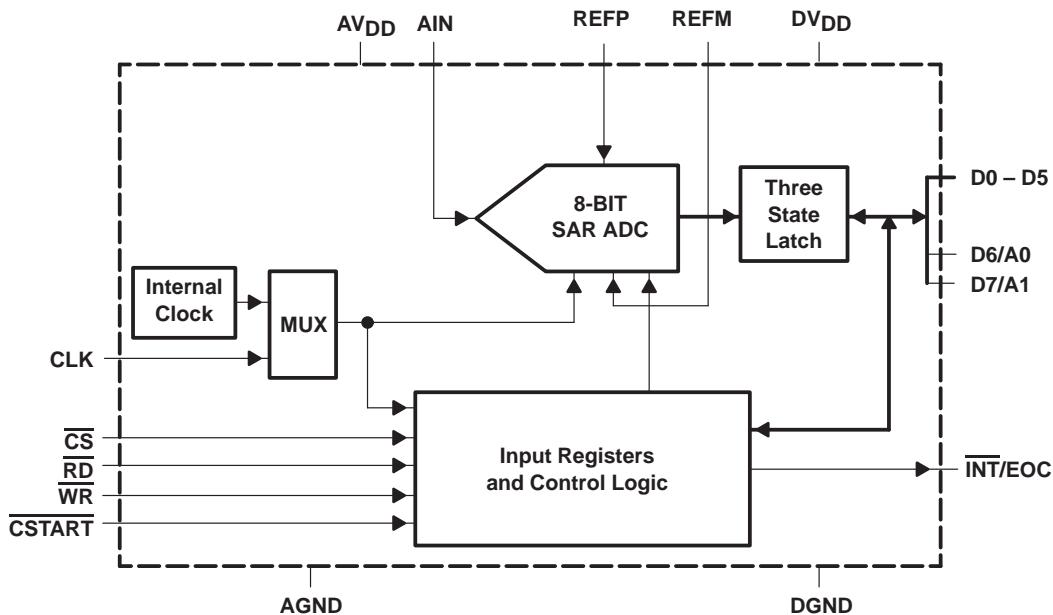
## AVAILABLE OPTIONS

T <sub>A</sub>	PACKAGE	
	24 TSSOP (PW)	24 SOIC (DW)
−40°C to 85°C	TLV571IPW	TLV571IDW



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

## functional block diagram



## Terminal Functions

TERMINAL		I/O	DESCRIPTION
NAME	NO.		
AGND	21		Analog ground
AIN	23	I	ADC analog input
AVDD	22		Analog supply voltage, 2.7 V to 5.5 V
A0/D6	16	I/O	Bidirectional 3-state data bus. D6/A0 along with D7/A1 is used as address lines to access CR0 and CR1 for initialization.
A1/D7	17	I/O	Bidirectional 3-state data bus. D7/A1 along with D6/A0 is used as address lines to access CR0 and CR1 for initialization.
CLK	4	I	External clock input
CS	1	I	Chip select. A logic low on CS enables the TLV571.
CSTART	18	I	Hardware sample and conversion start input. The falling edge of CSTART starts sampling and the rising edge of CSTART starts conversion.
DGND	5, 8, 9		Digital ground
DVDD	6		Digital supply voltage, 2.7 V to 5.5 V
D0 – D5	10–15	I/O	Bidirectional 3-state data bus
INT/EOC	7	O	End-of-conversion/interrupt
NC	24		Not connected
RD	3	I	Read data. A falling edge on RD enables a read operation on the data bus when CS is low.
REFM	20	I	Lower reference voltage (nominally ground). REFM must be supplied or REFM pin must be grounded.
REFP	19	I	Upper reference voltage (nominally AVDD). The maximum input voltage range is determined by the difference between the voltage applied to REFP and REFM.
WR	2	I	Write data. A rising edge on the WR latches in configuration data when CS is low. When using software conversion start, a rising edge on WR also initiates an internal sampling start pulse. When WR is tied to ground, the ADC in nonprogrammable (hardware configuration mode).

## detailed description

### analog-to-digital SAR converter

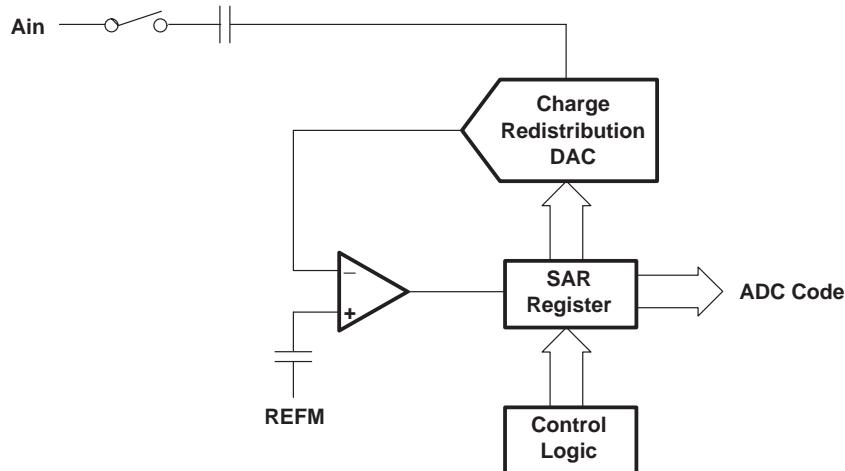


Figure 1

The TLV571 is a successive-approximation ADC utilizing a charge redistribution DAC. Figure 1 shows a simplified version of the ADC.

The sampling capacitor acquires the signal on Ain during the sampling period. When the conversion process starts, the SAR control logic and charge redistribution DAC are used to add and subtract fixed amounts of charge from the sampling capacitor to bring the comparator into a balanced condition. When the comparator is balanced, the conversion is complete and the ADC output code is generated.

### sampling frequency, $f_s$

The TLV571 requires 16 CLKs for each conversion, therefore the equivalent maximum sampling frequency achievable with a given CLK frequency is:

$$f_{s(\max)} = (1/16) f_{\text{CLK}}$$

The TLV571 is software configurable. The first two MSB bits, D(7,6) are used to address which register to set. The remaining six bits are used as control data bits. There are two control registers, CR0 and CR1, that are user configurable. All of the register bits are written to the control register during write cycles. A description of the control registers is shown in Figure 2.

**detailed description (continued)****control registers**

A1	A0	D5	D4	D3	D2	D1	D0
Control Register Zero (CR0)							
A(1:0)=00		D5	D4	D3	D2	D1	D0
		STARTSEL	PROGEOC	CLKSEL	SWPWDN	Don't Care	Don't Care
		0: HARDWARE START (CSTART) 1: SOFTWARE START	0: INT 1: EOC	0: Internal Clock 1: External Clock	0: NORMAL 1: Powerdown	Don't Care	Don't Care
Control Register One (CR1)							
A(1:0)=01		D5	D4	D3	D2	D1	D0
		Reserved	OSCSPD	0 Reserved	0 Reserved	OUTCODE	Reserved
		0: Reserved Bit Always Write 0	0: INT. OSC. SLOW 1: INT. OSC. FAST	0: Reserved Bit Always Write 0	0: Reserved Bit, Always Write 0	0: Binary 1: 2's Complement	0: Reserved Bit, Always Write 0

**Figure 2. Input Data Format****hardware configuration option**

The TLV571 can configure itself. This option is enabled when the WR pin is tied to ground and a dummy RD signal is applied. The ADC is now fully configured. Zeros or default values are applied to both control registers. The ADC is configured ideally for 3-V operation, which means the internal OSC is set at 10 MHz and hardware start of conversion using CSTART.

**ADC conversion modes**

The TLV571 provides two start of conversion modes. Table 1 explains these modes in more detail.

## detailed description (continued)

**Table 1. Conversion Modes**

START OF CONVERSION	OPERATION	COMMENTS – FOR INPUT
Hardware start (CSTART) CR0.D5 = 0	<ul style="list-style-type: none"> <li>Repeated conversions from AIN</li> <li>CSTART falling edge to start sampling</li> <li>CSTART rising edge to start conversion</li> <li>If in INT mode, one INT pulse generated after each conversion</li> <li>If in EOC mode, EOC will go high to low at start of conversion, and return high at end of conversion.</li> </ul>	CSTART rising edge must be applied a minimum of 5 ns before or after CLK rising edge.
Software start CR0.D5 = 1	<ul style="list-style-type: none"> <li>Repeated conversions from AIN</li> <li>WR rising edge to start sampling initially. Thereafter, sampling occurs at the rising edge of RD.</li> <li>Conversion begins after 6 clocks after sampling has begun. Thereafter, if in INT mode, one INT pulse generated after each conversion</li> <li>If in EOC mode, EOC will go high to low at start of conversion and return high at end of conversion.</li> </ul>	With external clock, WR and RD rising edge must be a minimum 5 ns before or after CLK rising edge.

### configure the device

The device can be configured by writing to control registers CR0 and CR1.

**Table 2. TLV571 Programming Examples**

REGISTER	INDEX		D5	D4	D3	D2	D1	D0	COMMENT
	D7	D6							
<b>EXAMPLE1</b>									
CR0	0	0	0	0	0	0	0	0	Normal, INT OSC
CR1	0	1	0	0	0	0	0	0	Binary
<b>EXAMPLE2</b>									
CR0	0	0	0	1	1	1	0	0	Power down, EXT OSC
CR1	0	1	0	0	0	0	1	0	2's complement output

### power down

The TLV571 offers two power down modes, auto power down and software power down. This device will automatically proceed to auto power down mode if RD is not present one clock after conversion. Software power down is controlled directly by the user by pulling CS to DV<sub>DD</sub>.

**Table 3. Power Down Modes**

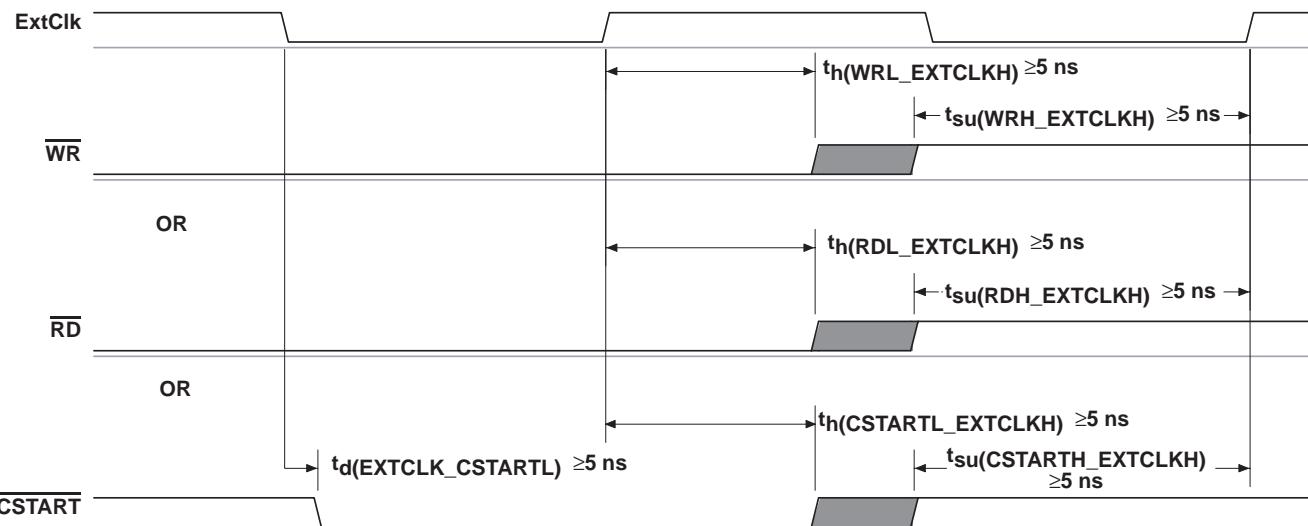
PARAMETERS/MODES	AUTO POWER DOWN	SOFTWARE POWER DOWN (CS = DV <sub>DD</sub> )
Maximum power down dissipation current	1 mA	10 $\mu$ A
Comparator	Power down	Power down
Clock buffer	Power down	Power down
Control registers	Saved	Saved
Minimum power down time	1 CLK	2 CLK
Minimum resume time	1 CLK	2 CLK

**detailed description (continued)****reference voltage input**

The TLV571 has two reference input pins: REFP and REFM. The voltage levels applied to these pins establish the upper and lower limits of the analog inputs to produce a full-scale and zero-scale reading respectively. The values of REFP, REFM, and the analog input should not exceed the positive supply or be less than GND consistent with the specified absolute maximum ratings. The digital output is at full scale when the input signal is equal to or higher than REFP and is at zero when the input signal is equal to or lower than REFM.

**sampling/conversion**

All sampling, conversion, and data output in the device are started by a trigger. This could be the  $\overline{RD}$ ,  $\overline{WR}$ , or  $\overline{CSTART}$  signal depending on the mode of conversion and configuration. The rising edge of  $\overline{RD}$ ,  $\overline{WR}$ , and  $\overline{CSTART}$  signal are extremely important, since they are used to start the conversion. These edges need to stay close to the rising edge of the external clock (if it is used as CLK). The minimum setup and hold time with respect to the rising edge of the external clock should be 5 ns minimum. When the internal clock is used, this is not an issue since these two edges will start the internal clock automatically. Therefore, the setup time is always met. Software controlled sampling lasts 6 clock cycles. This is done via the CLK input or the internal oscillator if enabled. The input clock frequency can be 1 MHz to 20 MHz, translating into a sampling time from 0.6  $\mu$ s to 0.3  $\mu$ s. The internal oscillator frequency is 9 MHz minimum (oscillator frequency is between 9 MHz to 22 MHz), translating into a sampling time from 0.6  $\mu$ s to 0.3  $\mu$ s. Conversion begins immediately after sampling and lasts 10 clock cycles. This is again done using the external clock input (1 MHz–20 MHz) or the internal oscillator (9 MHz minimum) if enabled. Hardware controlled sampling, via  $\overline{CSTART}$ , begins on falling  $\overline{CSTART}$  lasts the length of the active  $\overline{CSTART}$  signal. This allows more control over the sampling time, which is useful when sampling sources with large output impedances. On rising  $\overline{CSTART}$ , conversion begins. Conversion in hardware controlled mode also lasts 10 clock cycles. This is done using the external clock input (1 MHz–20 MHz) or the internal oscillator (9 MHz minimum) as is the case in software controlled mode.



NOTE:  $t_{su}$  = setup time,  $t_h$  = hold time

**Figure 3. Trigger Timing – Software Start Mode Using External Clock**

## start of conversion mechanism

There are two ways to convert data: hardware and software. In the hardware conversion mode the ADC begins sampling at the falling edge of CSTART and begins conversion at the rising edge of CSTART. Software start mode ADC samples for 6 clocks, then conversion occurs for ten clocks. The total sampling and conversion process lasts only 16 clocks in this case. If RD is not detected during the next clock cycle, the ADC automatically proceeds to a power-down state. Data is valid on the rising edge of INT in both conversion modes.

### hardware CSTART conversion

#### *external clock*

With CS low and WR low, data is written into the ADC. The sampling begins at the falling edge of CSTART and conversion begins at the rising edge of CSTART. At the end of conversion, EOC goes from low to high, telling the host that conversion is ready to be read out. The external clock is active and is used as the reference at all times. With this mode, it is required that CSTART is not applied at the rising edge of the clock (see Figure 4).

start of conversion mechanism (continued)

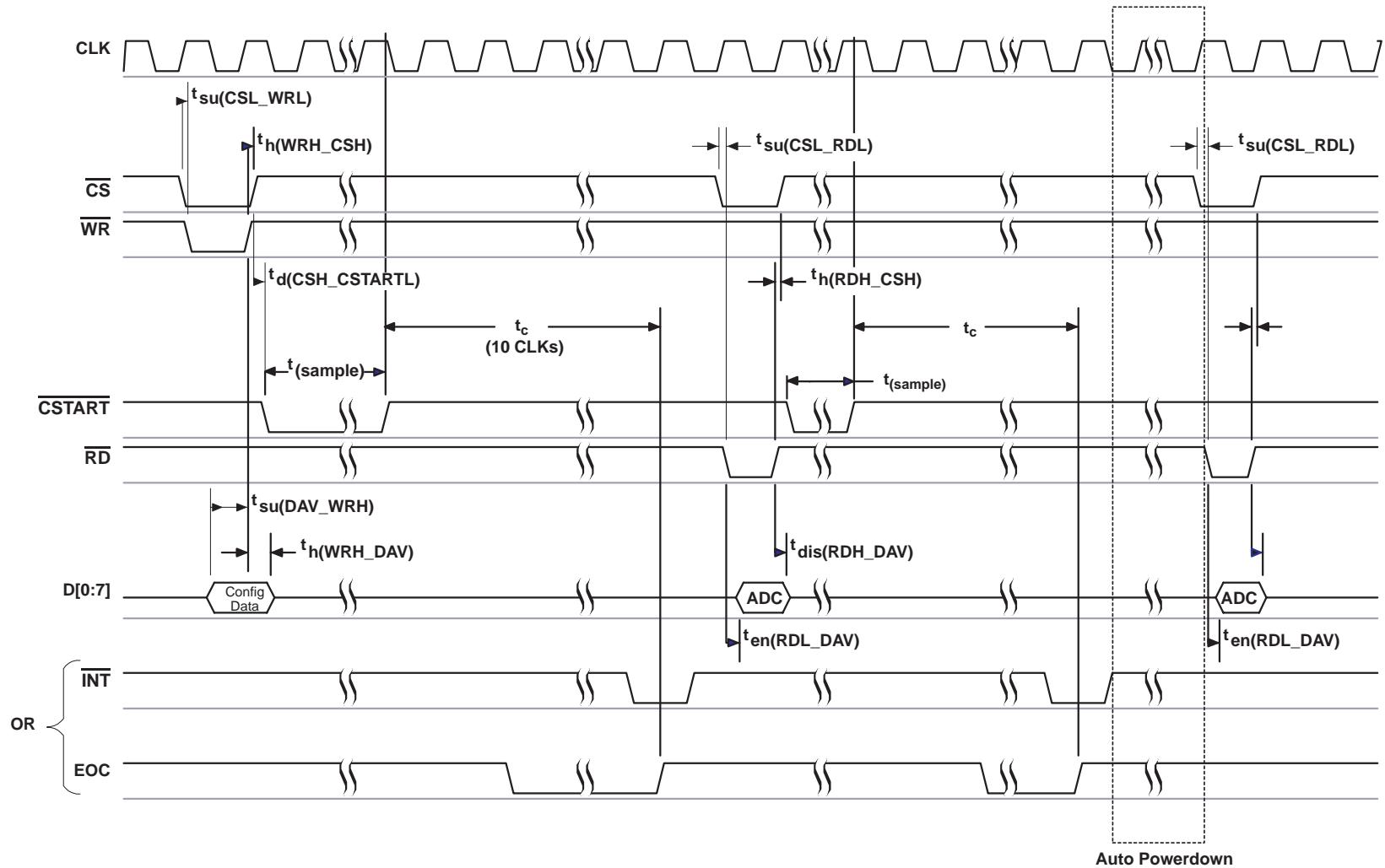


Figure 4. Input Conversion – Hardware CSTART, External Clock

### internal clock

With  $\overline{CS}$  low and  $\overline{WR}$  low, data is written into the ADC. The sampling begins at the falling edge of  $\overline{CSTART}$ , and conversion begins at the rising edge of  $\overline{CSTART}$ . The internal clock turns on at the rising edge of  $\overline{CSTART}$ . The internal clock is disabled after each conversion.

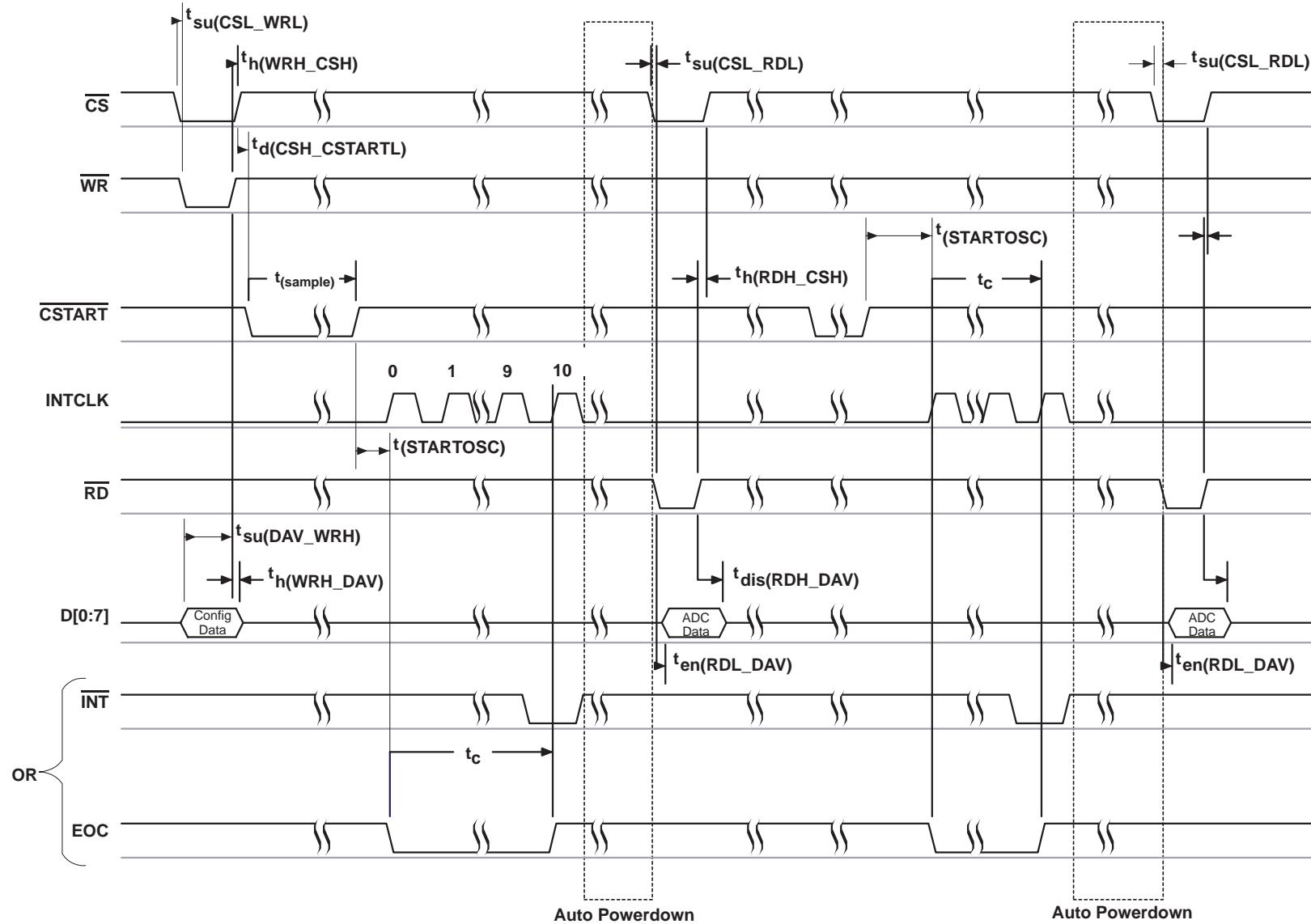
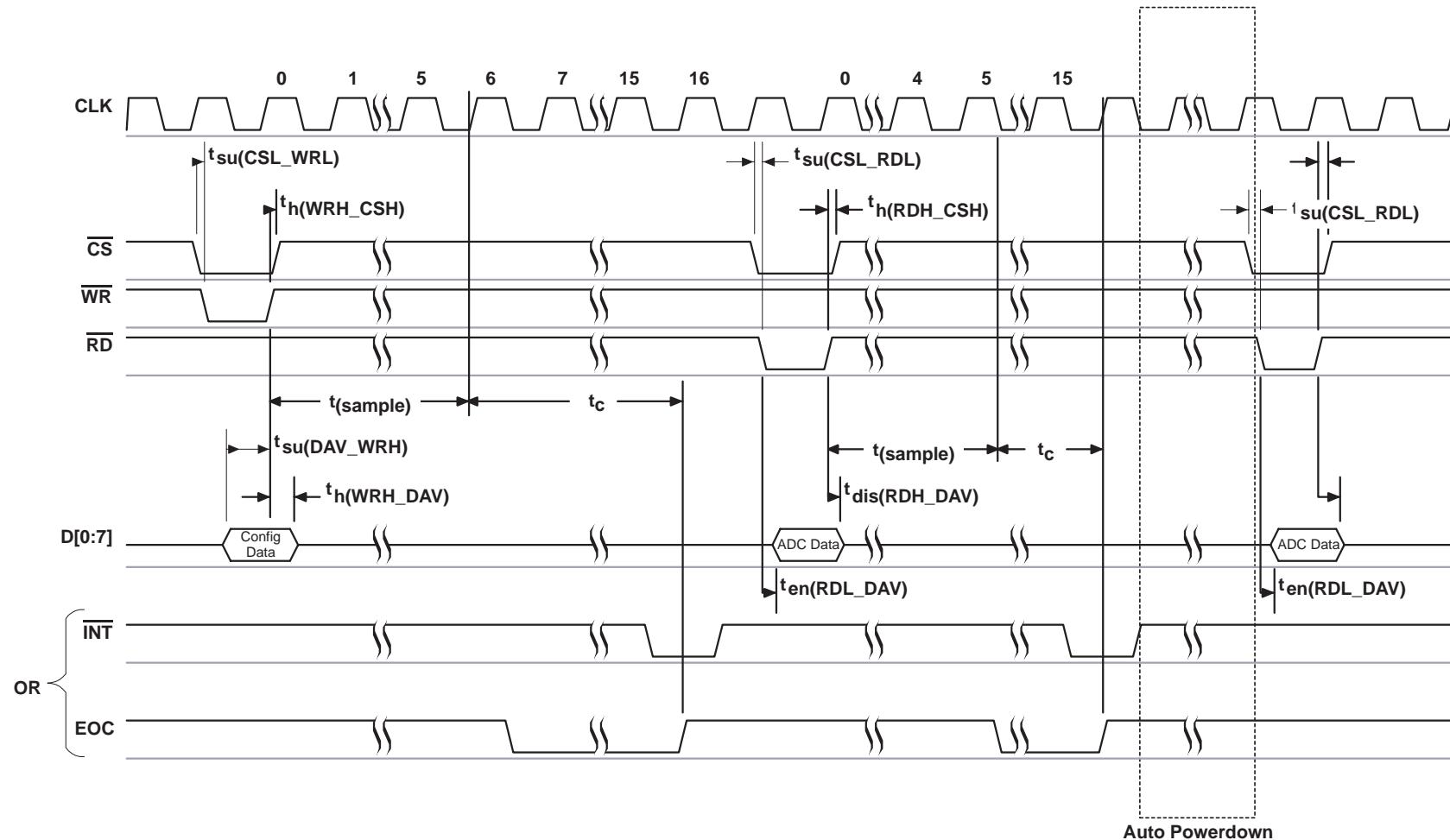


Figure 5. Input Conversion – Hardware  $\overline{CSTART}$ , Internal Clock

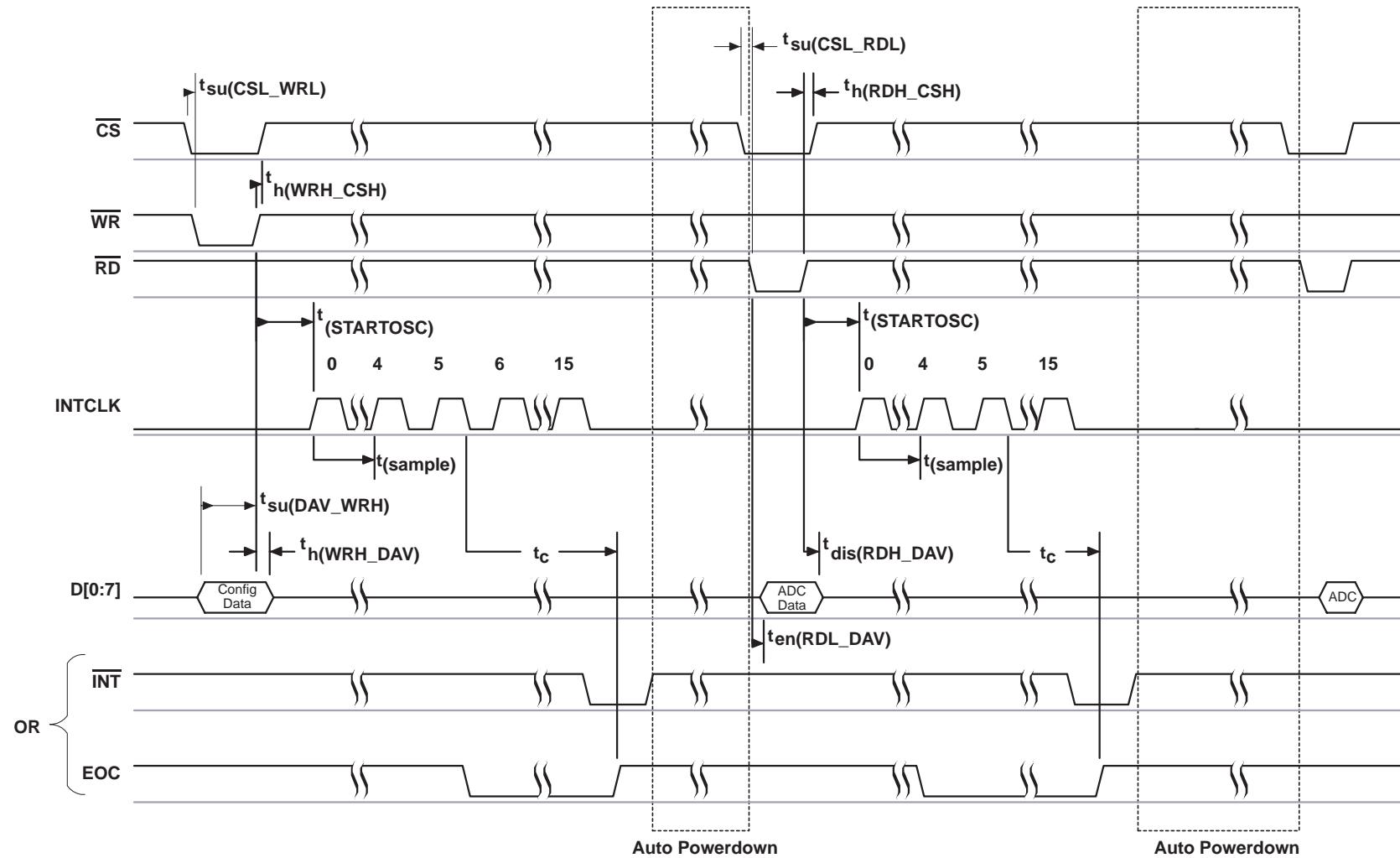
**software START conversion**
**external clock**

With  $\overline{CS}$  low and  $\overline{WR}$  low, data is written into the ADC. Sampling begins at the rising edge of  $\overline{WR}$ . The conversion process begins 6 clocks after sampling begins. At the end of conversion, the  $\overline{INT}$  goes low telling the host that conversion is ready to be read out. EOC B low during the conversion. The external clock is active and used as the reference at all times. With this mode,  $\overline{WR}$  and  $\overline{RD}$  should not be applied at the rising edge of the clock (see Figure 3).


**Figure 6. Input Conversion – Software Start, External Clock**

**software START conversion (continued)**
**internal clock**

With  $\overline{CS}$  low and  $\overline{WR}$  low, data is written into the ADC. Sampling begins at the rising edge of  $\overline{WR}$ . Conversion begins 6 clocks after sampling begins. The internal clock begins at the rising edge of  $\overline{WR}$ . The internal clock is disabled after each conversion. Subsequent sampling begins at the rising edge of  $\overline{RD}$ .


**Figure 7. Input Conversion – Software Start, Internal Clock**

**software START conversion (continued)****system clock source**

The TLV571 internally derives multiple clocks from the SYSCLK for different tasks. SYSCLK is used for most conversion subtasks. The source of SYSCLK is programmable via control register zero, bit 3. The source of SYSCLK is changed at the rising edge of WR of the cycle when CR0.D3 is programmed.

**internal clock (CR0.D3 = 0, SYSCLK = internal OSC)**

The TLV571 has a built-in 10 MHz OSC. When the internal OSC is selected as the source of SYSCLK, the internal clock starts with a delay (one half of the OSC period max) after the falling edge of the conversion trigger (either WR, RD, or CSTART). The OSC speed can be set to  $10 \pm 1$  MHz or  $20 \pm 2$  MHz by setting register bit CR1.D4.

**external clock (CR0.D3 = 1, SYSCLK = external clock)**

The TLV571 is designed to accept an external clock input (CMOS/TTL logic) with frequencies from 1 MHz to 20 MHz.

**host processor interface**

The TLV571 provides a generic high-speed parallel interface that is compatible with high-performance DSPs and general-purpose microprocessors. The interface includes D(0–7), INT/EOC, RD, and WR.

**output format**

The data output format is unipolar (code 0 to 255). The output code format can be either binary or two's complement by setting register bit CR1.D1.

**power up and initialization**

After power up, CS must be low to begin an I/O cycle. INT/EOC is initially high. The TLV571 requires two write cycles to configure the two control registers. The first conversion after the device has returned from the power down state may be invalid and should be disregarded.

**definitions of specifications and terminology****integral nonlinearity**

Integral nonlinearity refers to the deviation of each individual code from a line drawn from zero through full scale. The point used as zero occurs 1/2 LSB before the first code transition. The full-scale point is defined as level 1/2 LSB beyond the last code transition. The deviation is measured from the center of each particular code to the true straight line between these two points.

**differential nonlinearity**

An ideal ADC exhibits code transitions that are exactly 1 LSB apart. DNL is the deviation from this ideal value. A differential nonlinearity error of less than  $\pm 1$  LSB ensures no missing codes.

**zero offset**

The major carry transition should occur when the analog input is at zero volts. Zero error is defined as the deviation of the actual transition from that point.

**gain error**

The first code transition should occur at an analog value 1/2 LSB above negative full scale. The last transition should occur at an analog value 1 1/2 LSB below the nominal full scale. Gain error is the deviation of the actual difference between first and last code transitions and the ideal difference between first and last code transitions.

### software START conversion (continued)

#### signal-to-noise ratio + distortion (SINAD)

Signal-to-noise ratio + distortion is the ratio of the rms value of the measured input signal to the rms sum of all other spectral components below the Nyquist frequency, including harmonics but excluding dc. The value for SINAD is expressed in decibels.

#### effective number of bits (ENOB)

For a sine wave, SINAD can be expressed in terms of the number of bits. Using the following formula,

$$N = (\text{SINAD} - 1.76)/6.02$$

it is possible to get a measure of performance expressed as N, the effective number of bits. Thus, the effective number of bits for a device for sine wave inputs at a given input frequency can be calculated directly from its measured SINAD.

#### total harmonic distortion (THD)

Total harmonic distortion is the ratio of the rms sum of the first six harmonic components to the rms value of the measured input signal and is expressed as a percentage or in decibels.

#### spurious free dynamic range (SFDR)

Spurious free dynamic range is the difference in dB between the rms amplitude of the input signal and the peak spurious signal.

### DSP interface

The TLV571 is a 8-bit single input channel analog-to-digital converter with throughput up to 1.25 MSPS at 5 V and up to 625 KSPS at 3 V. To achieve 1.25 MSPS throughput, the ADC must be clocked at 20 MHz. Likewise to achieve 625 KSPS throughout, the ADC must be clocked at 10 MHz. The TLV571 can be easily interfaced to microcontrollers, ASICs, and DSPs. Figure 8 shows the pin connections to interface the TLV571 to the TMS320C6x DSP.

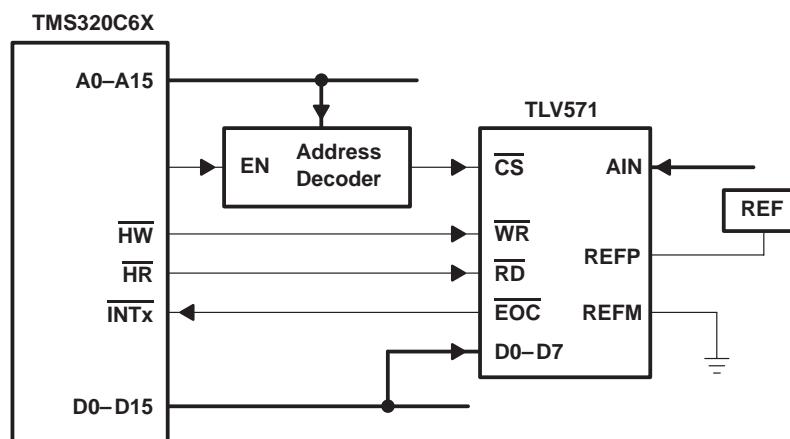


Figure 8. TMS320C6x DSP Interface

## grounding and decoupling considerations

General practices should apply to the PCB design to limit high frequency transients and noise that are fed back into the supply and reference lines. This requires that the supply and reference pins be sufficiently bypassed. In most cases 0.1- $\mu$ F ceramic chip capacitors are adequate to keep the impedance low over a wide frequency range. Since their effectiveness depends largely on the proximity to the individual supply pin, they should be placed as close to the supply pins as possible.

To reduce high frequency and noise coupling, it is highly recommended that digital and analog grounds be shorted immediately outside the package. This can be accomplished by running a low impedance line between DGND and AGND under the package.

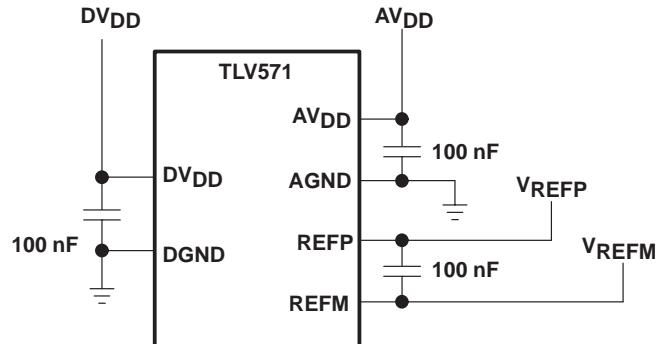
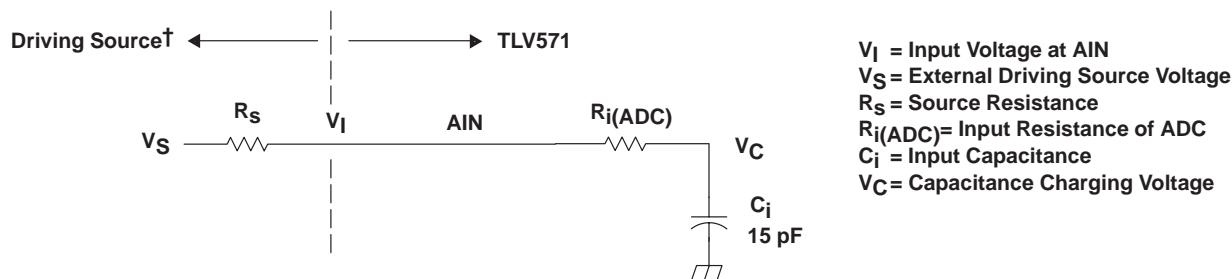


Figure 9. Placement for Decoupling Capacitors

## power supply ground layout

Printed-circuit boards that use separate analog and digital ground planes offer the best system performance. Wire-wrap boards do not perform well and should not be used. The two ground planes should be connected together at the low-impedance power-supply source. The best ground connection may be achieved by connecting the ADC AGND terminal to the system analog ground plane making sure that analog ground currents are well managed.



† Driving source requirements:

- Noise and distortion for the source must be equivalent to the resolution of the converter.
- $R_S$  must be real at the input frequency.

Figure 10. Equivalent Input Circuit Including the Driving Source

## simplified analog input analysis

Using the equivalent circuit in Figure 10, the time required to charge the analog input capacitance from 0 to  $V_S$  within 1/2 LSB,  $t_{ch}$ (1/2 LSB), can be derived as follows.

The capacitance charging voltage is given by:

$$V_{C(t)} = V_S \left( 1 - e^{-t_{ch}/R_t C_i} \right)$$

Where

$$R_t = R_s + R_i \quad (1)$$

$$R_i = R_i(\text{ADC})$$

$$t_{ch} = \text{Charge time}$$

The input impedance  $R_i$  is  $718 \Omega$  at 5 V, and is higher ( $\sim 1.25 \text{ k}\Omega$ ) at 2.7 V. The final voltage to 1/2 LSB is given by:

$$V_C(1/2 \text{ LSB}) = V_S - (V_S/512) \quad (2)$$

Equating equation 1 to equation 2 and solving for cycle time  $t_C$  gives:

$$V_S - (V_S/512) = V_S \left( 1 - e^{-t_{ch}/R_t C_i} \right) \quad (3)$$

and time to change to 1/2 LSB (minimum sampling time) is:

$$t_{ch}(1/2 \text{ LSB}) = R_t \times C_i \times \ln(512)$$

Where

$$\ln(512) = 6.238$$

Therefore, with the values given, the time for the analog input signal to settle is:

$$t_{ch}(1/2 \text{ LSB}) = (R_s + 718 \Omega) \times 15 \text{ pF} \times \ln(512) \quad (4)$$

This time must be less than the converter sample time shown in the timing diagrams. Which is 6x SCLK.

$$t_{ch}(1/2 \text{ LSB}) \leq 6 \times 1/f(\text{SCLK}) \quad (5)$$

Therefore the maximum SCLK frequency is:

$$\text{Max}(f(\text{SCLK})) = 6/t_{ch}(1/2 \text{ LSB}) = 6/(\ln(512) \times R_t \times C_i) \quad (6)$$

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)<sup>†</sup>

Supply voltage, GND to $V_{CC}$ .....	–0.3 V to 6.5 V
Analog input voltage range .....	–0.3 V to $AV_{DD} + 0.3$ V
Reference input voltage range .....	$AV_{DD} + 0.3$ V
Digital input voltage range .....	–0.3 V to $DV_{DD} + 0.3$ V
Operating virtual junction temperature range, $T_J$ .....	–40°C to 150°C
Operating free-air temperature range, $T_A$ , .....	–40°C to 85°C
Storage temperature range, $T_{STG}$ .....	–65°C to 150°C
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds .....	260°C

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

## recommended operating conditions

## power supplies

	MIN	MAX	UNIT
Analog supply voltage, $AV_{DD}$	2.7	5.5	V
Digital supply voltage, $DV_{DD}$	2.7	5.5	V

NOTE 1: Abs ( $AV_{DD} - DV_{DD}$ ) < 0.5 V

## analog inputs

	MIN	MAX	UNIT
Analog input voltage, AIN	AGND	VREFP	V

## digital inputs

	MIN	NOM	MAX	UNIT
High-level input voltage, $V_{IH}$	$DV_{DD} = 2.7$ V to 5.5 V	2.1	2.4	V
Low level input voltage, $V_{IL}$	$DV_{DD} = 2.7$ V to 5.5 V		0.8	V
Input CLK frequency	$DV_{DD} = 4.5$ V to 5.5 V		20	MHz
	$DV_{DD} = 2.7$ V to 3.3 V		10	MHz
Pulse duration, CLK high, $t_w(CLKH)$	$DV_{DD} = 4.5$ V to 5.5 V, $f_{CLK} = 20$ MHz	23		ns
	$DV_{DD} = 2.7$ V to 3.3 V, $f_{CLK} = 10$ MHz	46		ns
Pulse duration, CLK low, $t_w(CLKL)$	$DV_{DD} = 4.5$ V to 5.5 V, $f_{CLK} = 20$ MHz	23		ns
	$DV_{DD} = 2.7$ V to 3.3 V, $f_{CLK} = 10$ MHz	46		ns
Rise time, I/O and control, CLK, $\overline{CS}$	50 pF output load	4		ns
Fall time, I/O and control, CLK, $\overline{CS}$	50 pF output load	4		

## reference specifications

		MIN	NOM	MAX	UNIT
External reference voltage	VREFP	$AV_{DD} = 3$ V	2	$AV_{DD}$	V
		$AV_{DD} = 5$ V	2.5	$AV_{DD}$	V
	VREFM	$AV_{DD} = 3$ V	AGND	1	V
		$AV_{DD} = 5$ V	AGND	2	V
	VREFP – VREFM		2	$AV_{DD} - AGND$	V

electrical characteristics over recommended operating free-air temperature range, supply voltages, and reference voltages (unless otherwise noted)

**digital specifications**

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
<b>Logic inputs</b>					
$I_{IH}$	High-level input current $DV_{DD} = 5 \text{ V}, DV_{DD} = 3 \text{ V}, \text{Input} = DV_{DD}$	-1	1		$\mu\text{A}$
$I_{IL}$	Low-level input current $DV_{DD} = 5 \text{ V}, DV_{DD} = 3 \text{ V}, \text{Input} = 0 \text{ V}$	-1	1		$\mu\text{A}$
$C_i$	Input capacitance		10	15	$\text{pF}$
<b>Logic outputs</b>					
$V_{OH}$	High-level output voltage $I_{OH} = 50 \mu\text{A} \text{ to } 0.5 \text{ mA}$	$DV_{DD} - 0.4$			$\text{V}$
$V_{OL}$	Low-level output voltage $I_{OL} = 50 \mu\text{A} \text{ to } 0.5 \text{ mA}$		0.4		$\text{V}$
$I_{OZ}$	High-impedance-state output current $DV_{DD} = 5 \text{ V}, DV_{DD} = 3 \text{ V}, \text{Input} = DV_{DD}$		1		$\mu\text{A}$
$I_{OL}$	Low-impedance-state output current $DV_{DD} = 5 \text{ V}, DV_{DD} = 3 \text{ V}, \text{Input} = 0 \text{ V}$		-1		$\mu\text{A}$
$C_o$	Output capacitance		5		$\text{pF}$
Internal clock	3 V, $AV_{DD} = DV_{DD}$	9	10	11	$\text{MHz}$
	5 V, $AV_{DD} = DV_{DD}$	18	20	22	

**dc specifications**

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT	
Resolution		8			Bits	
<b>Accuracy</b>						
Integral nonlinearity, INL	Best fit	$\pm 0.3$	$\pm 0.5$		LSB	
Differential nonlinearity, DNL		$\pm 0.3$	$\pm 0.5$		LSB	
Missing codes			0			
$E_O$	Offset error	$\pm 0.15\%$	$\pm 0.3\%$		FSR	
$E_G$	Gain error	$\pm 0.2\%$	$\pm 0.4\%$		FSR	
<b>Analog input</b>						
$C_i$	AIN, $AV_{DD} = 3 \text{ V}, DV_{DD} = 5 \text{ V}$	15			$\text{pF}$	
	MUX input, $AV_{DD} = 3 \text{ V}, DV_{DD} = 5 \text{ V}$	25			$\text{pF}$	
$I_{lkg}$	$V_{AIN} = 0 \text{ to } DV_{DD}$		$\pm 1$		$\mu\text{A}$	
<b>Voltage reference input</b>						
$r_i$	Input resistance	2			$\text{k}\Omega$	
$C_i$	Input capacitance		300		$\text{pF}$	
<b>Power supply</b>						
Operating supply current, $I_{DD} + I_{REF}$		$AV_{DD} = DV_{DD} = 3 \text{ V}, f_{CLK} = 10 \text{ MHz}$	4	5.5	$\text{mA}$	
		$AV_{DD} = DV_{DD} = 5 \text{ V}, f_{CLK} = 20 \text{ MHz}$	7	8.5	$\text{mA}$	
PD	Power dissipation	$AV_{DD} + DV_{DD} = 3 \text{ V}$	12	17	$\text{mW}$	
		$AV_{DD} + DV_{DD} = 5 \text{ V}$	35	43	$\text{mW}$	
$I_{PD}$	Supply current in power-down mode	Software	$I_{DD} + I_{REF}$	1	$\mu\text{A}$	
			$AV_{DD} = 3 \text{ V}$	2	$\mu\text{A}$	
	Auto		$AV_{DD} = 3 \text{ V}$	0.5	$\text{mA}$	
			$AV_{DD} = 5 \text{ V}$	0.5	$\text{mA}$	

electrical characteristics over recommended operating free-air temperature range, supply voltages, and reference voltages (unless otherwise noted) (continued)

ac specifications,  $AV_{DD} = DV_{DD} = 5$  V (unless otherwise noted)

PARAMETER	TEST CONDITIONS		MIN	TYP	MAX	UNIT
Signal-to-noise ratio, SNR	$f_I = 100$ kHz, 80% of FS	$f_S = 1.25$ MSPS, $AV_{DD} = 5$ V	47	49		dB
		$f_S = 625$ KSPS, $AV_{DD} = 3$ V	47	49		dB
Signal-to-noise ratio + distortion, SINAD	$f_I = 100$ kHz, 80% of FS	$f_S = 1.25$ MSPS, $AV_{DD} = 5$ V	47	49		dB
		$f_S = 625$ KSPS, $AV_{DD} = 3$ V	47	49		dB
Total harmonic distortion, THD	$f_I = 100$ kHz, 80% of FS	$f_S = 1.25$ MSPS, $AV_{DD} = 5$ V		–64	–52	dB
		$f_S = 625$ KSPS, $AV_{DD} = 3$ V		–62	–52	dB
Effective number of bits, ENOB	$f_I = 100$ kHz, 80% of FS	$f_S = 1.25$ MSPS, $AV_{DD} = 5$ V	7.5	7.9		Bits
		$f_S = 625$ KSPS, $AV_{DD} = 3$ V	7.5	7.9		Bits
Spurious free dynamic range, SFDR	$f_I = 100$ kHz, 80% of FS	$f_S = 1.25$ MSPS, $AV_{DD} = 5$ V		–65	–51	dB
		$f_S = 625$ KSPS, $AV_{DD} = 3$ V		–64	–51	dB
<b>Analog input</b>						
Full-power bandwidth	–1 dB	Full-scale 0 dB input sine wave	12	18		MHz
	–3 dB	Full-scale 0 dB input sine wave		30		MHz
Small-signal bandwidth	–1 dB	–20 dB input sine wave	15	20		MHz
	–3 dB	–20 dB input sine wave		35		MHz
Sampling rate, $f_S$	$AV_{DD} = 4.5$ V to 5.5 V		0.0625		1.25	MSPS
	$AV_{DD} = 2.7$ V to 3.3 V		0.0625		0.625	MSPS

**timing requirements,  $AV_{DD} = DV_{DD} = 5$  V (unless otherwise noted)**

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$t_c(CLK)$ Input clock Cycle time	$DV_{DD} = 4.5$ V to 5.5 V	50			ns
	$DV_{DD} = 2.7$ V to 3.3 V	100			ns
$t_{(sample)}$ Reset and sampling time			6		SYSCLK Cycles
$t_c$ Total conversion time			10		SYSCLK Cycles
$t_{wL}(EOC)$ Pulse width, end of conversion, EOC			10		SYSCLK Cycles
$t_{wL}(INT)$ Pulse width, interrupt			1		SYSCLK Cycles
$t_{(STARTOSC)}$ Start-up time, internal oscillator		100			ns
$t_d(CSH\_CSTARTL)$ Delay time, $\overline{CS}$ high to $\overline{CSTART}$ low		10			ns
$t_{en}(RDL\_DAV)$ Enable time, data out	$DV_{DD} = 5$ V at 50 pF	20			ns
	$DV_{DD} = 3$ V at 50 pF	40			ns
$t_{dis}(RDH\_DAV)$ Disable time, data out	$DV_{DD} = 5$ V at 50 pF	5			ns
	$DV_{DD} = 3$ V at 50 pF	10			ns
$t_{su}(CSL\_WRL)$ Setup time, $\overline{CS}$ to $\overline{WR}$		5			ns
$t_h(WRH\_CSH)$ Hold time, $\overline{CS}$ to $\overline{WR}$		5			ns
$t_w(WR)$ Pulse width, write		1			Clock Period
$t_w(RD)$ Pulse width, read		1			Clock Period
$t_{su}(DAV\_WRH)$ Setup time, data valid to $\overline{WR}$		10			ns
$t_h(WRH\_DAV)$ Hold time, data valid to $\overline{WR}$		5			ns
$t_{su}(CSL\_RDL)$ Setup time, $\overline{CS}$ to $\overline{RD}$		5			ns
$t_h(RDH\_CSH)$ Hold time, $\overline{CS}$ to $\overline{RD}$		5			ns
$t_h(WRL\_EXTXLKH)$ Hold time $\overline{WR}$ to clock high		5			ns
$t_h(RDL\_EXTCLKH)$ Hold time $\overline{RD}$ to clock high		5			ns
$t_h(CSTARTL\_EXTCLKH)$ Hold time $\overline{CSTART}$ to clock high		5			ns
$t_{su}(WRH\_EXTCLKH)$ Setup time $\overline{WR}$ high to clock high		5			ns
$t_{su}(RDH\_EXTCLKH)$ Setup time $\overline{RD}$ high to clock high		5			ns
$t_{su}(CSTARTh\_EXTCLKH)$ Setup time $\overline{CSTART}$ high to clock high		5			ns
$t_d(EXTCLK\_CSTARTL)$ Delay time clock low to $\overline{CSTART}$ low		5			ns

NOTE: Specifications subject to change without notice.

Data valid is denoted as DAV.

## TYPICAL CHARACTERISTICS

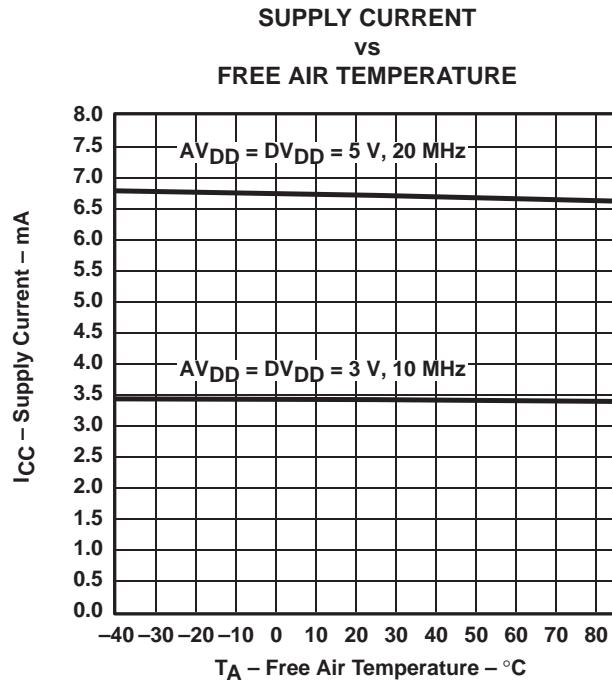


Figure 11

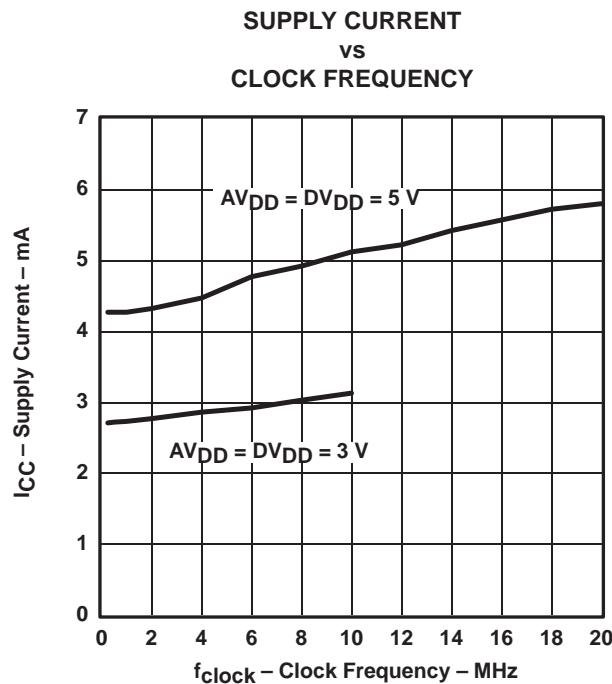


Figure 12

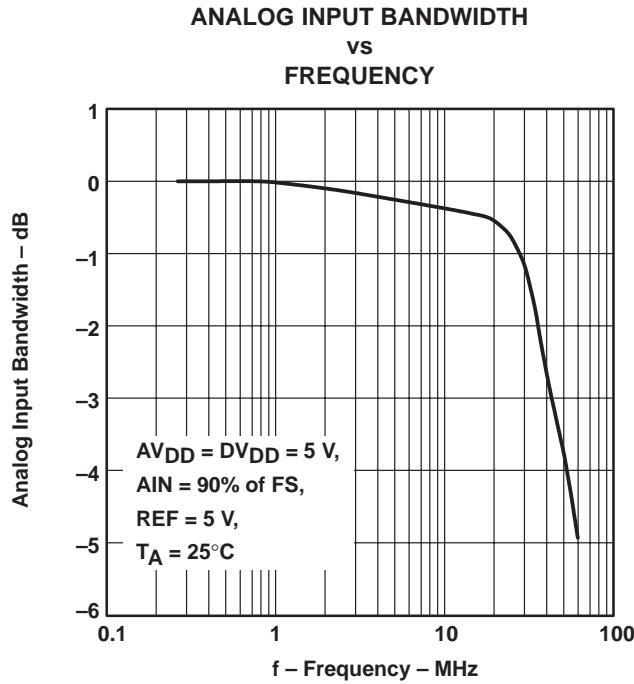
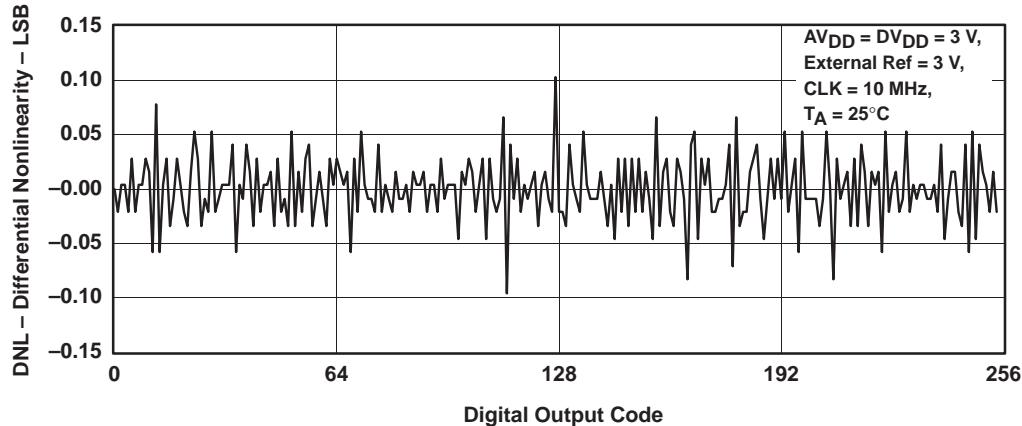


Figure 13

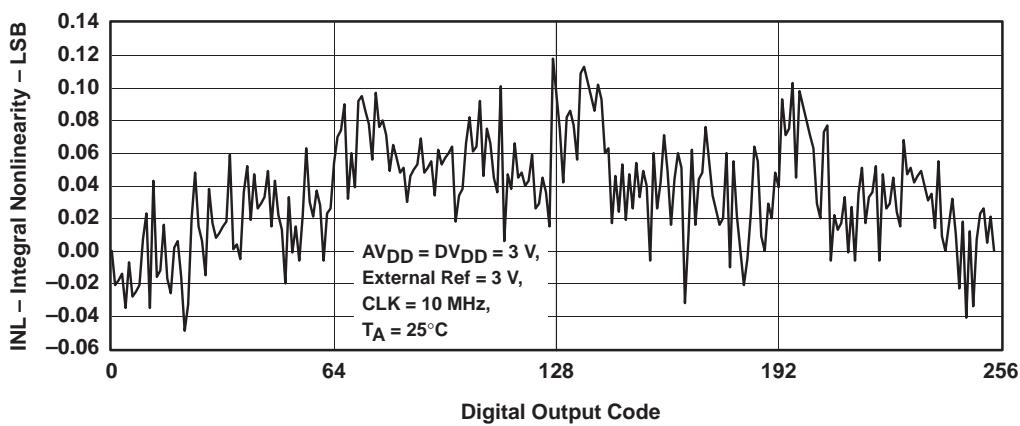
**TYPICAL CHARACTERISTICS**

**DIFFERENTIAL NONLINEARITY  
VS  
DIGITAL OUTPUT CODE**



**Figure 14**

**INTEGRAL NONLINEARITY  
VS  
DIGITAL OUTPUT CODE**



**Figure 15**

## TYPICAL CHARACTERISTICS

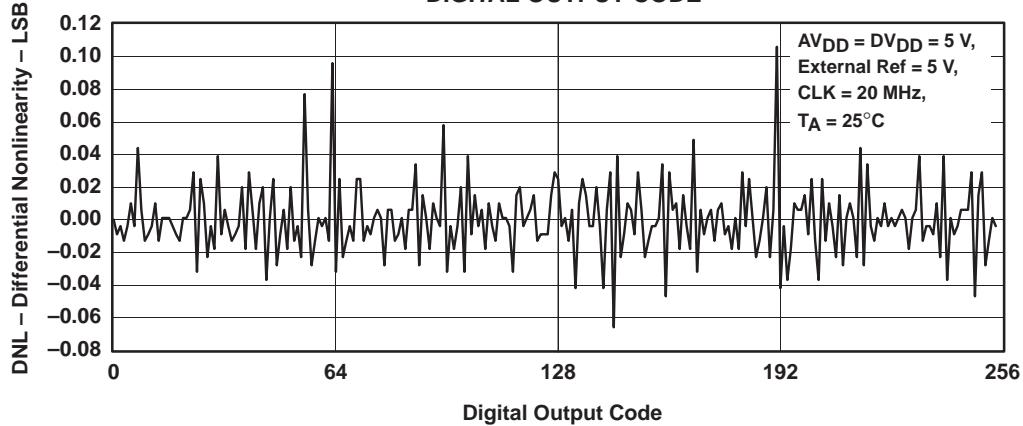
DIFFERENTIAL NONLINEARITY  
vs  
DIGITAL OUTPUT CODE

Figure 16

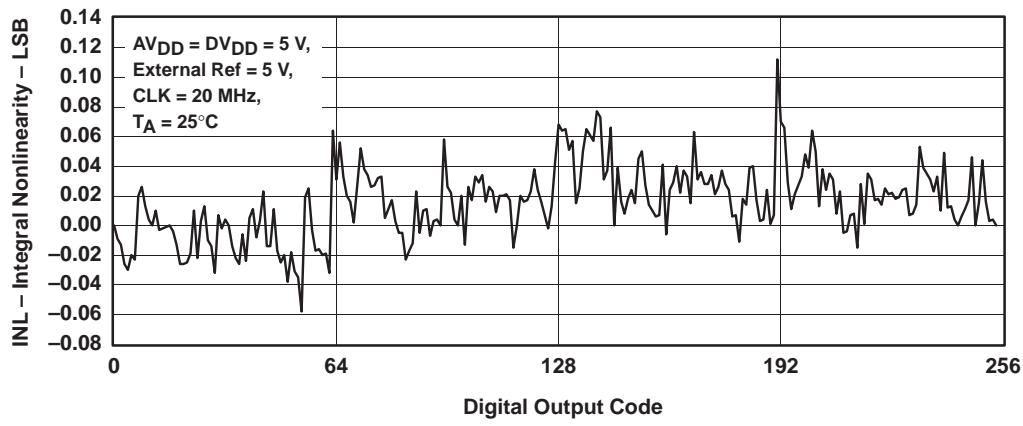
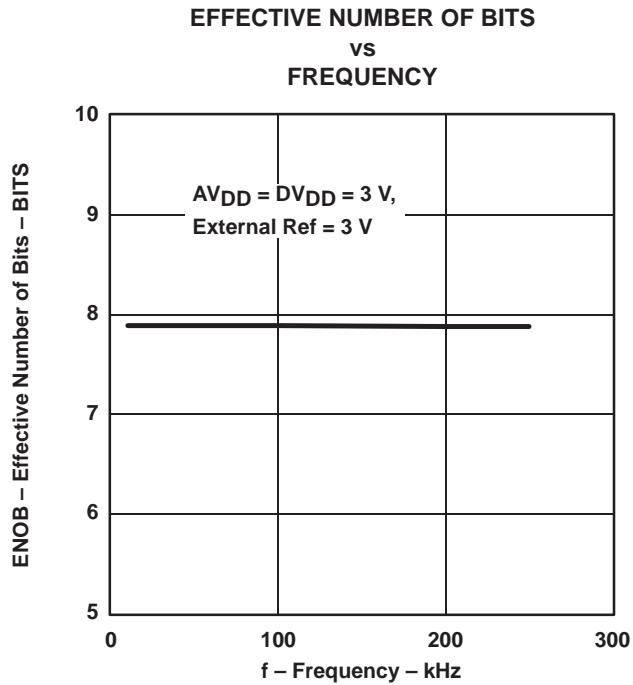
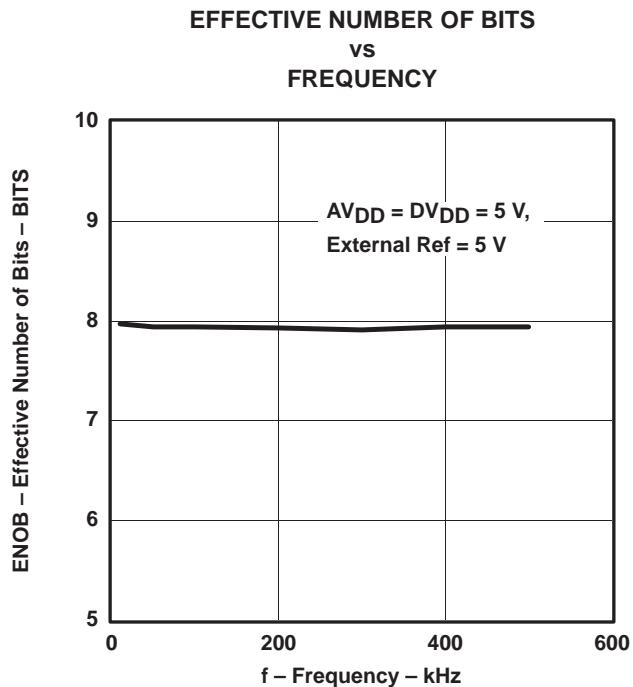
INTEGRAL NONLINEARITY  
vs  
DIGITAL OUTPUT CODE

Figure 17

## **TYPICAL CHARACTERISTICS**



**Figure 18**



**Figure 19**

TLV571

2.7 V TO 5.5 V, 1-CHANNEL, 8-BIT,  
PARALLEL ANALOG-TO-DIGITAL CONVERTER

SLAS239A – SEPTEMBER 1999 – REVISED FEBRUARY 2000

## TYPICAL CHARACTERISTICS

### FAST FOURIER TRANSFORM vs FREQUENCY

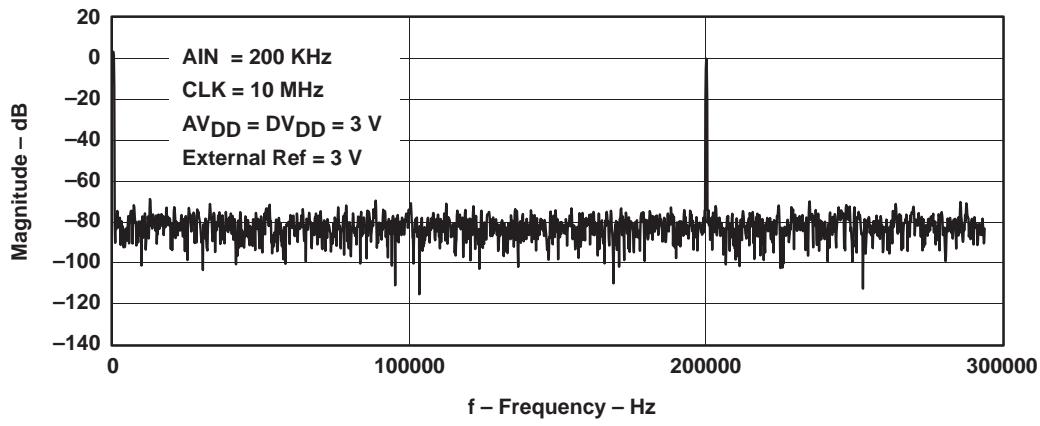


Figure 20

### FAST FOURIER TRANSFORM vs FREQUENCY

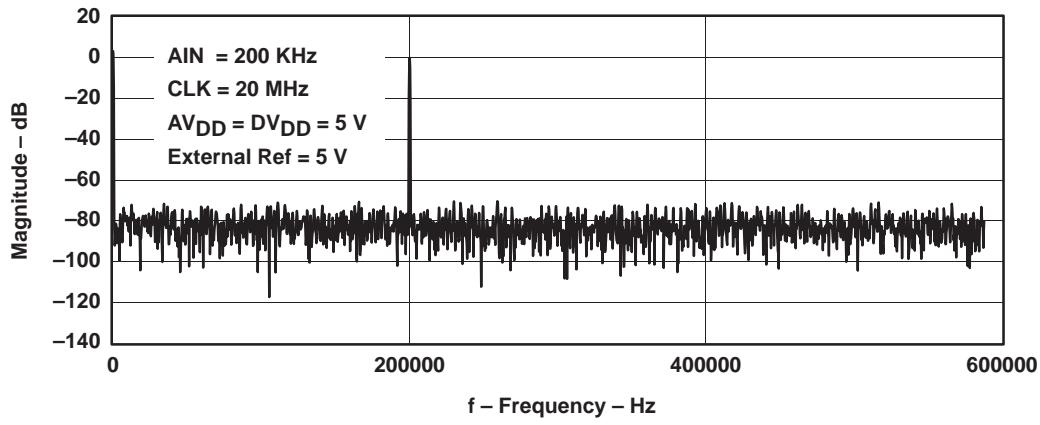


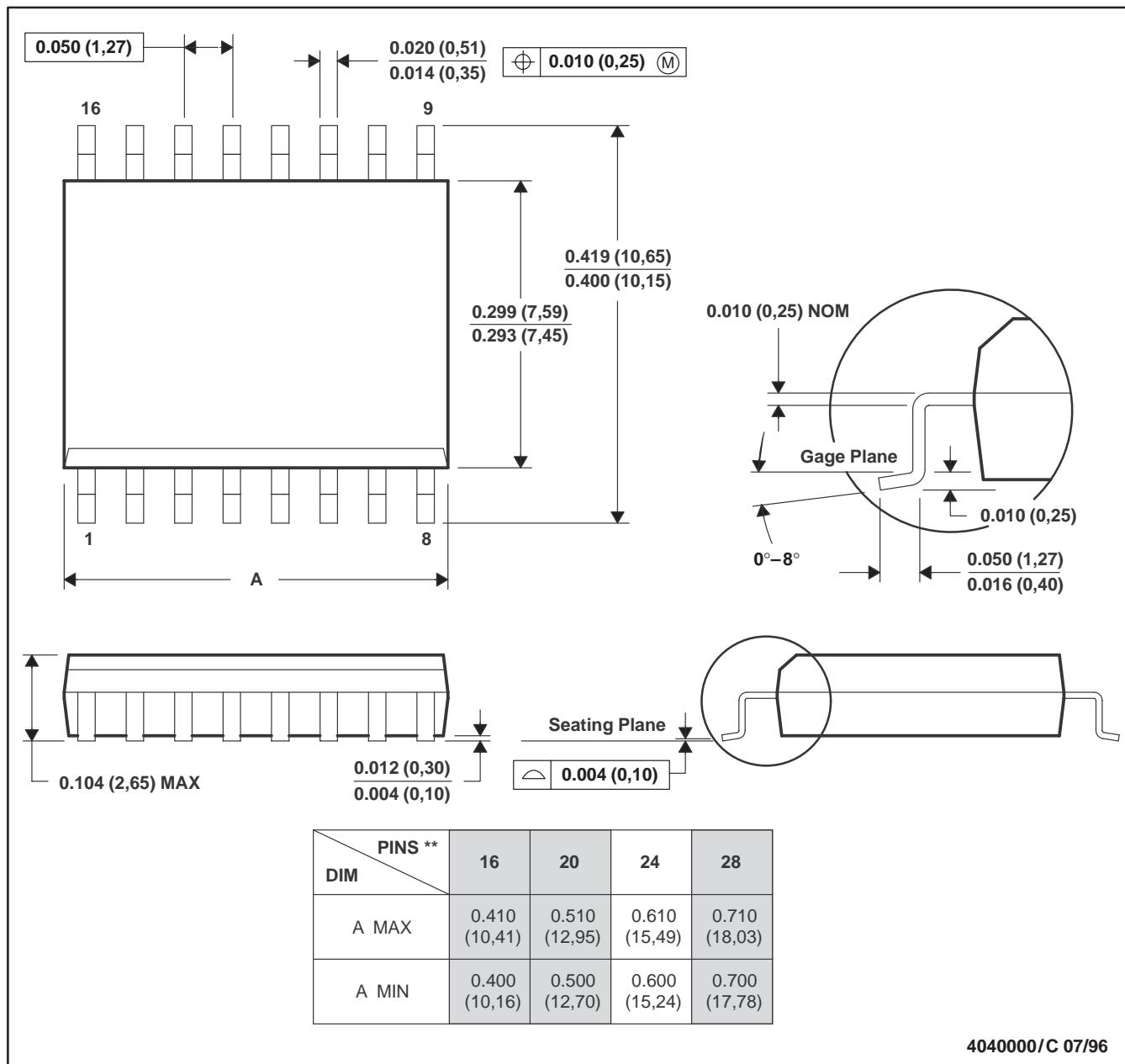
Figure 21

## MECHANICAL DATA

DW (R-PDSO-G\*\*)

16 PINS SHOWN

PLASTIC SMALL-OUTLINE PACKAGE



NOTES: A. All linear dimensions are in inches (millimeters).  
 B. This drawing is subject to change without notice.  
 C. Body dimensions do not include mold flash or protrusion not to exceed 0.006 (0.15).  
 D. Falls within JEDEC MS-013

TLV571

2.7 V TO 5.5 V, 1-CHANNEL, 8-BIT,  
PARALLEL ANALOG-TO-DIGITAL CONVERTER

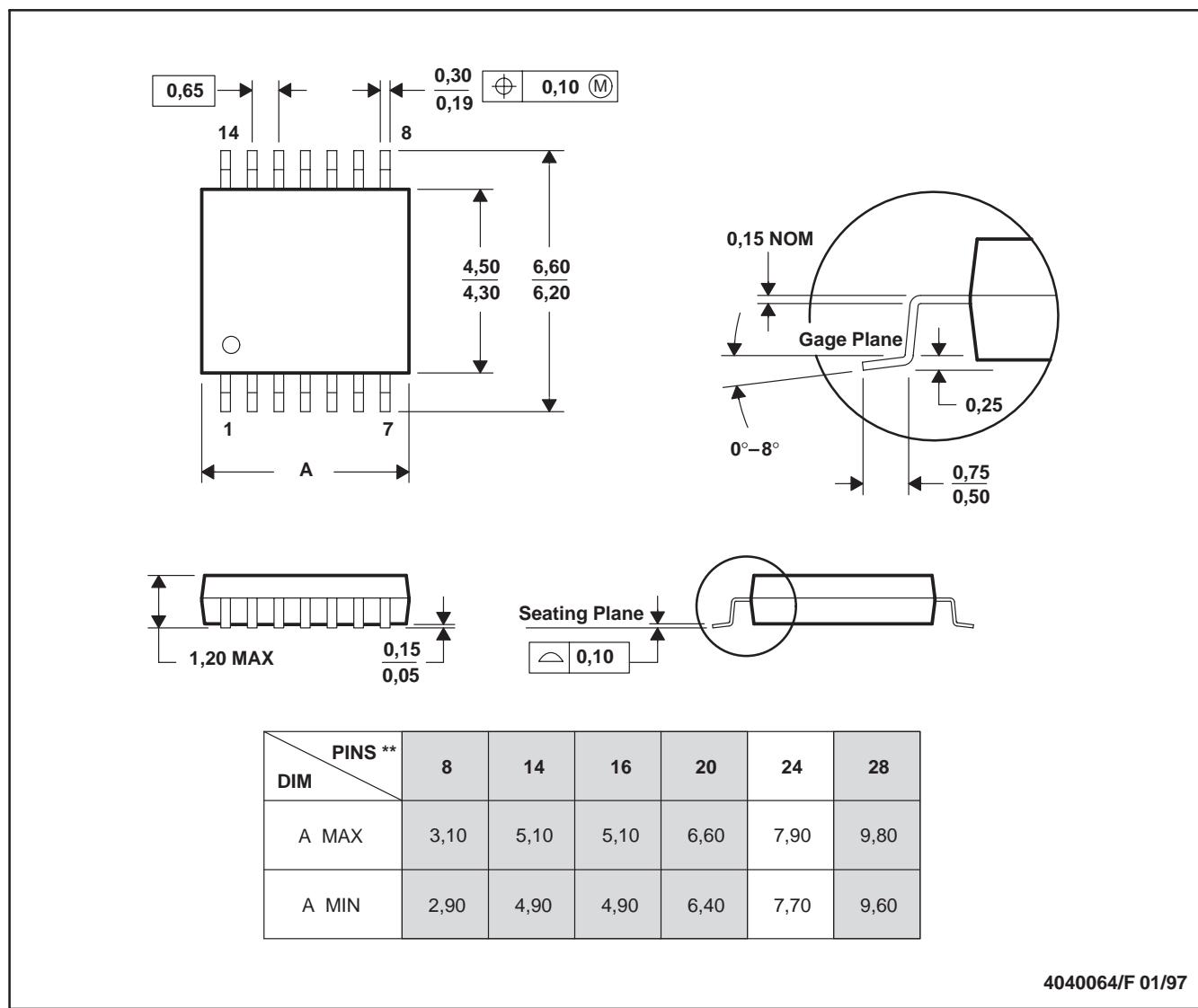
SLAS239A – SEPTEMBER 1999 – REVISED FEBRUARY 2000

## MECHANICAL DATA

PW (R-PDSO-G\*\*)

14 PINS SHOWN

PLASTIC SMALL-OUTLINE PACKAGE



4040064/F 01/97

NOTES: A. All linear dimensions are in millimeters.

B. This drawing is subject to change without notice.

C. Body dimensions do not include mold flash or protrusion not to exceed 0,15.

D. Falls within JEDEC MO-153

### **IMPORTANT NOTICE**

Texas Instruments and its subsidiaries (TI) reserve the right to make changes to their products or to discontinue any product or service without notice, and advise customers to obtain the latest version of relevant information to verify, before placing orders, that information being relied on is current and complete. All products are sold subject to the terms and conditions of sale supplied at the time of order acknowledgement, including those pertaining to warranty, patent infringement, and limitation of liability.

TI warrants performance of its semiconductor products to the specifications applicable at the time of sale in accordance with TI's standard warranty. Testing and other quality control techniques are utilized to the extent TI deems necessary to support this warranty. Specific testing of all parameters of each device is not necessarily performed, except those mandated by government requirements.

CERTAIN APPLICATIONS USING SEMICONDUCTOR PRODUCTS MAY INVOLVE POTENTIAL RISKS OF DEATH, PERSONAL INJURY, OR SEVERE PROPERTY OR ENVIRONMENTAL DAMAGE ("CRITICAL APPLICATIONS"). TI SEMICONDUCTOR PRODUCTS ARE NOT DESIGNED, AUTHORIZED, OR WARRANTED TO BE SUITABLE FOR USE IN LIFE-SUPPORT DEVICES OR SYSTEMS OR OTHER CRITICAL APPLICATIONS. INCLUSION OF TI PRODUCTS IN SUCH APPLICATIONS IS UNDERSTOOD TO BE FULLY AT THE CUSTOMER'S RISK.

In order to minimize risks associated with the customer's applications, adequate design and operating safeguards must be provided by the customer to minimize inherent or procedural hazards.

TI assumes no liability for applications assistance or customer product design. TI does not warrant or represent that any license, either express or implied, is granted under any patent right, copyright, mask work right, or other intellectual property right of TI covering or relating to any combination, machine, or process in which such semiconductor products or services might be or are used. TI's publication of information regarding any third party's products or services does not constitute TI's approval, warranty or endorsement thereof.

Copyright © 2000, Texas Instruments Incorporated